

# 2N7002BKS

# 60 V, 300 mA dual N-channel Trench MOSFET

Rev. 2 — 23 September 2010

**Product data sheet** 

### 1. Product profile

#### 1.1 General description

Dual N-channel enhancement mode Field-Effect Transistor (FET) in a very small SOT363 (SC-88) Surface-Mounted Device (SMD) plastic package using Trench MOSFET technology.

#### 1.2 Features and benefits

- Logic-level compatible
- Very fast switching
- Trench MOSFET technology
- ESD protection up to 2 kV
- AEC-Q101 qualified

### 1.3 Applications

- Relay driver
- High-speed line driver
- Low-side loadswitch
- Switching circuits

#### 1.4 Quick reference data

Table 1. Quick reference data

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$V_{DS}$	drain-source voltage	$T_{amb} = 25  ^{\circ}C$	-	-	60	V
$V_{GS}$	gate-source voltage	T <sub>amb</sub> = 25 °C	-	-	±20	V
$I_D$	drain current	$T_{amb}$ = 25 °C; $V_{GS}$ = 10 V	[1] -	-	300	mA
R <sub>DSon</sub>	drain-source on-state resistance	$T_j = 25  ^{\circ}\text{C};$ $V_{GS} = 10  \text{V};$ $I_D = 500  \text{mA}$	-	1	1.6	Ω

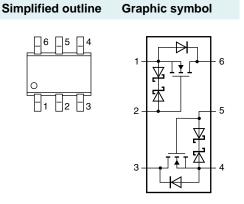
<sup>[1]</sup> Device mounted on an FR4 PCB, single-sided copper, tin-plated, mounting pad for drain 1 cm<sup>2</sup>.



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# 2. Pinning information

Table 2. **Pinning** Pin **Symbol** Description 1 S1 source 1 2 G1 gate 1 3 D2 drain 2 4 S2 source 2 5 G2 gate 2 6 D1 drain 1



017aaa055

# 3. Ordering information

Table 3. Ordering information

Type number	Package					
	Name	Description	Version			
2N7002BKS	SC-88	plastic surface-mounted package; 6 leads	SOT363			

# 4. Marking

Table 4. Marking codes

Type number	Marking code <sup>[1]</sup>
2N7002BKS	ZT*

[1] \* = -: made in Hong Kong

\* = p: made in Hong Kong

\* = t: made in Malaysia

\* = W: made in China

# 5. Limiting values

Table 5. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
Per trans	sistor				
$V_{DS}$	drain-source voltage	T <sub>amb</sub> = 25 °C	-	60	V
$V_{GS}$	gate-source voltage	T <sub>amb</sub> = 25 °C	-	±20	V
I <sub>D</sub>	drain current	$V_{GS} = 10 \text{ V}$	<u>[1]</u>		
		T <sub>amb</sub> = 25 °C	-	300	mA
		T <sub>amb</sub> = 100 °C	-	215	mA

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 Table 5.
 Limiting values ...continued

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
$I_{DM}$	peak drain current	$T_{amb}$ = 25 °C; single pulse; $t_p \le 10 \mu s$	-	1.2	Α
P <sub>tot</sub>	total power dissipation	T <sub>amb</sub> = 25 °C	[2] _	295	mW
			<u>[1]</u> _	340	mW
		$T_{sp} = 25  ^{\circ}C$	-	1040	mW
Source-dr	ain diode				
Is	source current	T <sub>amb</sub> = 25 °C	<u>[1]</u> _	300	mA
ESD max	imum rating				
$V_{ESD}$	electrostatic discharge voltage	human body model	[3] _	2000	V
Per device	ee				
P <sub>tot</sub>	total power dissipation	T <sub>amb</sub> = 25 °C	[2] _	445	mW
Tj	junction temperature			150	°C
T <sub>amb</sub>	ambient temperature		-55	+150	°C
T <sub>stg</sub>	storage temperature		-65	+150	°C

- [1] Device mounted on an FR4 PCB, single-sided copper, tin-plated, mounting pad for drain 1 cm<sup>2</sup>.
- [2] Device mounted on an FR4 Printed-Circuit Board (PCB), single-sided copper, tin-plated and standard footprint.
- [3] Measured between all pins.

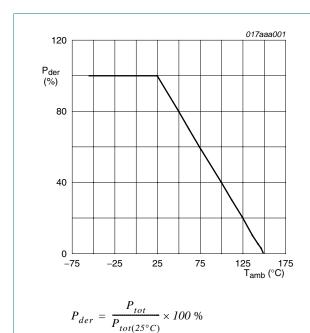
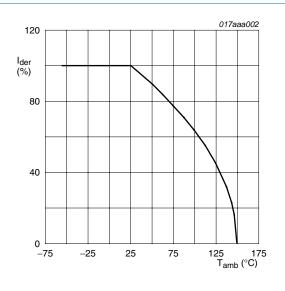


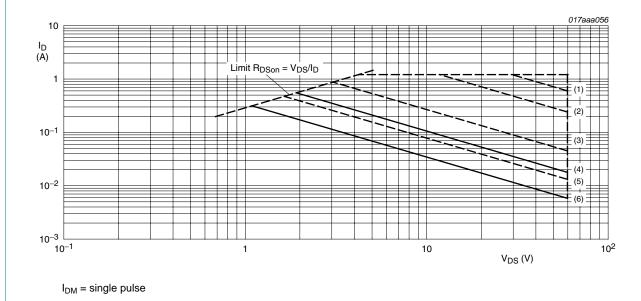
Fig 1. Normalized total power dissipation as a function of ambient temperature



$$I_{der} = \frac{I_D}{I_{D(25^{\circ}C)}} \times 100 \%$$

Fig 2. Normalized continuous drain current as a function of ambient temperature

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- (1)  $t_p = 100 \mu s$
- (2)  $t_p = 1 \text{ ms}$
- (3)  $t_p = 10 \text{ ms}$
- (4) DC;  $T_{sp} = 25 \, ^{\circ}C$
- (5)  $t_p = 100 \text{ ms}$
- (6) DC;  $T_{amb} = 25 \, ^{\circ}C$ ; drain mounting pad 1 cm<sup>2</sup>

Fig 3. Safe operating area; junction to ambient; continuous and peak drain currents as a function of drain-source voltage

#### 6. Thermal characteristics

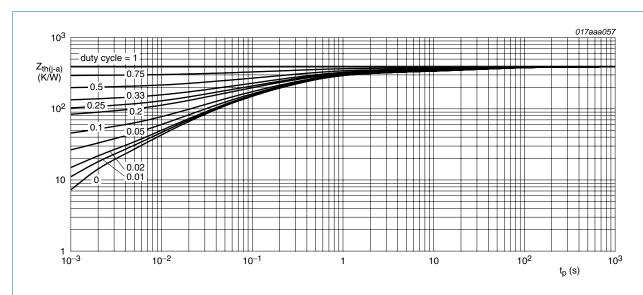
Table 6. Thermal characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Per transis	tor					
· -ui(j-a)	thermal resistance from junction to ambient	in free air	<u>[1]</u> -	370	425	K/W
			[2] _	320	370	K/W
$R_{th(j-sp)}$	thermal resistance from junction to solder point		-	-	120	K/W
Per device						
$R_{\text{th(j-a)}}$	thermal resistance from junction to ambient	in free air	<u>[1]</u> -	-	275	K/W

<sup>[1]</sup> Device mounted on an FR4 PCB, single-sided copper, tin-plated and standard footprint.

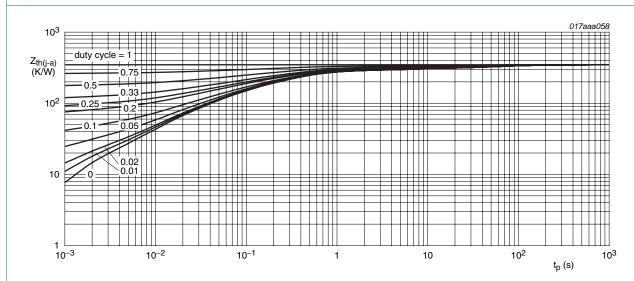
<sup>[2]</sup> Device mounted on an FR4 PCB, single-sided copper, tin-plated, mounting pad for drain 1 cm<sup>2</sup>.

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FR4 PCB, standard footprint

Fig 4. Transient thermal impedance from junction to ambient as a function of pulse duration; typical values



FR4 PCB, mounting pad for drain 1 cm<sup>2</sup>

Fig 5. Transient thermal impedance from junction to ambient as a function of pulse duration; typical values

### 60 V, 300 mA dual N-channel Trench MOSFET

## 7. Characteristics

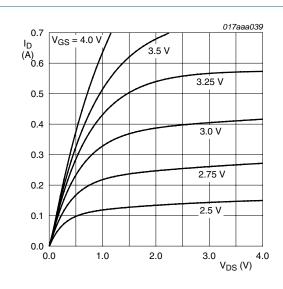
Table 7. Characteristics

 $T_i = 25$  °C unless otherwise specified.

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static cha	racteristics					
$V_{(BR)DSS}$	drain-source breakdown voltage	$I_D = 10 \mu A; V_{GS} = 0 V$	60	-	-	V
$V_{GS(th)}$	gate-source threshold voltage	$I_D = 250 \ \mu A; \ V_{DS} = V_{GS}$	1.1	1.6	2.1	V
I <sub>DSS</sub>	drain leakage current	$V_{DS} = 60 \text{ V}; V_{GS} = 0 \text{ V}$				
		T <sub>j</sub> = 25 °C	-	-	1	μΑ
		T <sub>j</sub> = 150 °C	-	-	10	μΑ
I <sub>GSS</sub>	gate leakage current	$V_{GS} = \pm 20 \text{ V}; V_{DS} = 0 \text{ V}$	-	-	10	μΑ
R <sub>DSon</sub>	drain-source on-state resistance		[1]			
		$V_{GS} = 5 \text{ V}; I_D = 50 \text{ mA}$	-	1.3	2	Ω
		$V_{GS} = 10 \text{ V}; I_D = 500 \text{ mA}$	-	1	1.6	Ω
g <sub>fs</sub>	forward transconductance	$V_{DS} = 10 \text{ V}; I_D = 200 \text{ mA}$	<u>[1]</u> _	550	-	mS
Dynamic o	characteristics					
Q <sub>G(tot)</sub>	total gate charge	$I_D = 300 \text{ mA};$	-	0.5	0.6	nC
$Q_{GS}$	gate-source charge	V <sub>DS</sub> = 30 V; - V <sub>GS</sub> = 4.5 V	-	0.2	-	nC
$Q_{GD}$	gate-drain charge	VGS = 4.5 V	-	0.1	-	nC
C <sub>iss</sub>	input capacitance	$V_{GS} = 0 \text{ V}; V_{DS} = 10 \text{ V};$	-	33	50	рF
Coss	output capacitance	f = 1 MHz	-	7	-	рF
C <sub>rss</sub>	reverse transfer capacitance		-	4	-	pF
t <sub>d(on)</sub>	turn-on delay time	$V_{DD} = 50 \text{ V};$	-	5	10	ns
t <sub>r</sub>	rise time	$R_L = 250 \Omega;$	-	6	-	ns
t <sub>d(off)</sub>	turn-off delay time	$-V_{GS} = 10 \text{ V};$ $R_G = 6 \Omega$	-	12	24	ns
t <sub>f</sub>	fall time		-	7	-	ns
Source-dr	ain diode					
$V_{SD}$	source-drain voltage	$I_S = 115 \text{ mA}; V_{GS} = 0 \text{ V}$	0.47	0.75	1.1	V

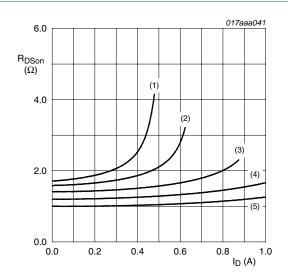
<sup>[1]</sup> Pulse test:  $t_p \le 300~\mu s;~\delta \le 0.01.$ 

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 $T_{amb} = 25 \, ^{\circ}C$ 

Fig 6. Output characteristics: drain current as a function of drain-source voltage; typical values



T<sub>amb</sub> = 25 °C

(1)  $V_{GS} = 3.25 \text{ V}$ 

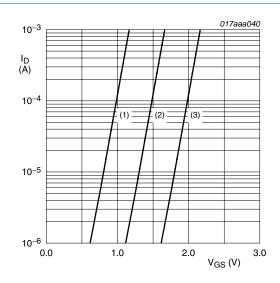
(2)  $V_{GS} = 3.5 \text{ V}$ 

(3)  $V_{GS} = 4 V$ 

(4)  $V_{GS} = 5 V$ 

(5)  $V_{GS} = 10 \text{ V}$ 

Fig 8. Drain-source on-state resistance as a function of drain current; typical values



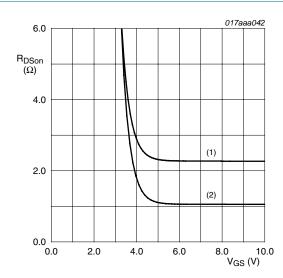
 $T_{amb}$  = 25 °C;  $V_{DS}$  = 5 V

(1) minimum values

(2) typical values

(3) maximum values

Fig 7. Sub-threshold drain current as a function of gate-source voltage



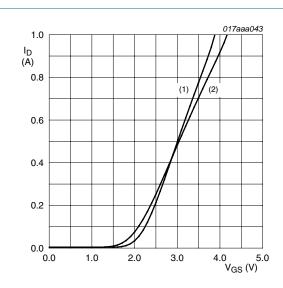
 $I_D = 500 \text{ mA}$ 

(1)  $T_{amb} = 150 \, ^{\circ}C$ 

(2)  $T_{amb} = 25 \, ^{\circ}C$ 

Fig 9. Drain-source on-state resistance as a function of gate-source voltage; typical values

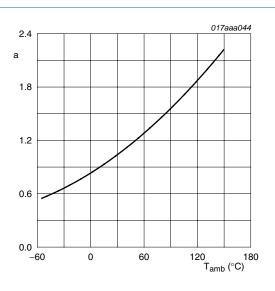
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$$V_{DS} > I_{D} \times R_{DSon}$$

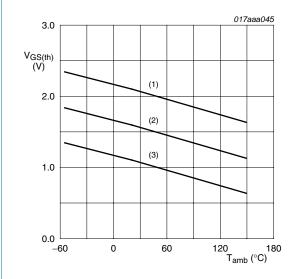
- (1)  $T_{amb} = 25 \, ^{\circ}C$
- (2)  $T_{amb} = 150 \, ^{\circ}C$

Fig 10. Transfer characteristics: drain current as a function of gate-source voltage; typical values



$$a = \frac{R_{DSon}}{R_{DSon(25^{\circ}C)}}$$

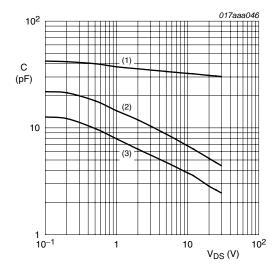
Fig 11. Normalized drain-source on-state resistance as a function of ambient temperature; typical values



 $I_D = 0.25 \text{ mA}; V_{DS} = V_{GS}$ 

- (1) maximum values
- (2) typical values
- (3) minimum values

Fig 12. Gate-source threshold voltage as a function of ambient temperature

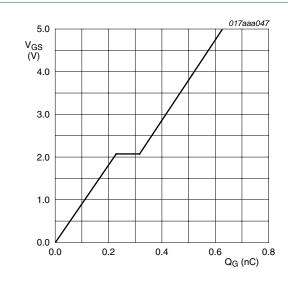


f = 1 MHz; V<sub>GS</sub> = 0 V

- (1) C<sub>iss</sub>
- (2) Coss
- (3)  $C_{rss}$

Fig 13. Input, output and reverse transfer capacitances as a function of drain-source voltage; typical values

#### 60 V, 300 mA dual N-channel Trench MOSFET



 $I_D$  = 300 mA;  $V_{DD}$  = 6 V;  $T_{amb}$  = 25 °C

Fig 14. Gate-source voltage as a function of gate charge; typical values

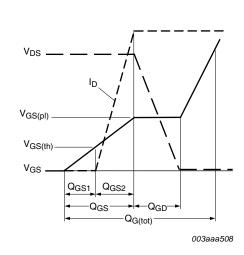
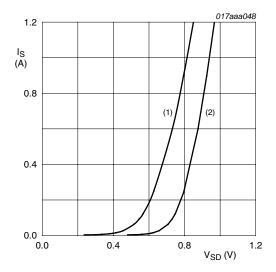


Fig 15. Gate charge waveform definitions



 $V_{GS} = 0 V$ 

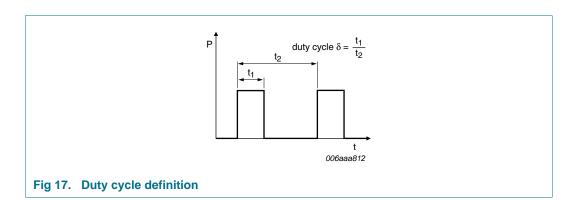
(1)  $T_{amb} = 150 \, ^{\circ}C$ 

(2)  $T_{amb} = 25 \, ^{\circ}C$ 

Fig 16. Source current as a function of source-drain voltage; typical values

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## 8. Test information



#### 60 V, 300 mA dual N-channel Trench MOSFET

## 9. Package outline

#### Plastic surface-mounted package; 6 leads

**SOT363** 

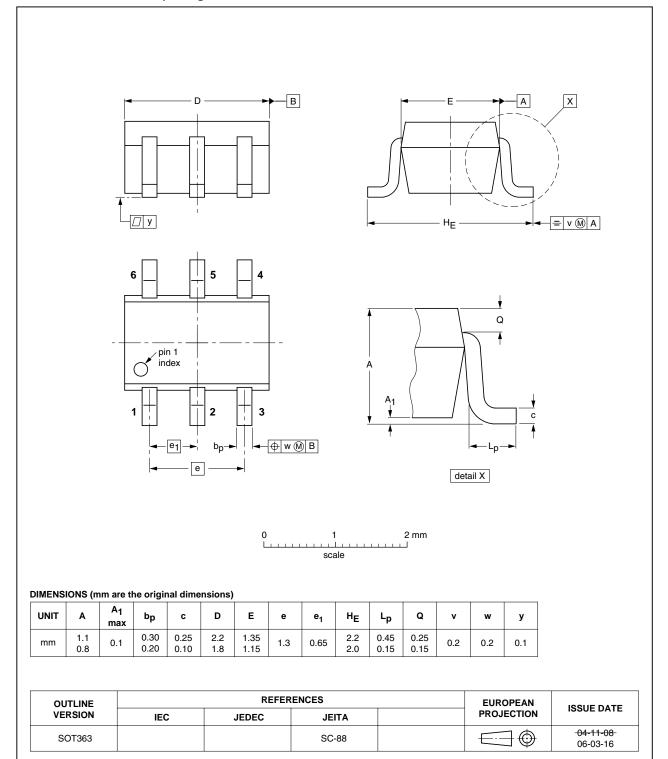


Fig 18. Package outline SOT363 (SC-88)

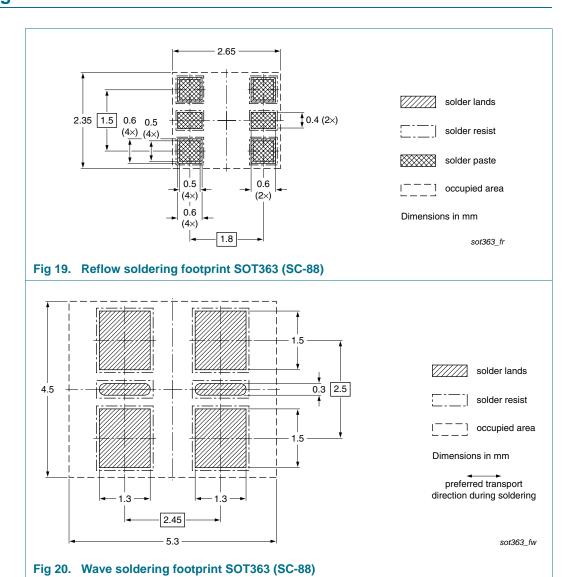
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#### 60 V, 300 mA dual N-channel Trench MOSFET

# 10. Soldering



## 60 V, 300 mA dual N-channel Trench MOSFET

# 11. Revision history

#### Table 8. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
2N7002BKS v.2	20100923	Product data sheet	-	2N7002BKS v.1
Modifications:	• Table 2 "Pin	ning": graphic symbol ame	nded	
2N7002BKS v.1	20100617	Product data sheet	-	-

#### 60 V, 300 mA dual N-channel Trench MOSFET

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#### 12.1 Data sheet status

Document status[1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- [1] Please consult the most recently issued document before initiating or completing a design.
- [2] The term 'short data sheet' is explained in section "Definitions"
- [3] The product status of device(s) described in this document may have changed since this document was published and may differ in case of multiple devices. The latest product status information is available on the Internet at URL <a href="http://www.nxp.com">http://www.nxp.com</a>.

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#### 60 V, 300 mA dual N-channel Trench MOSFET

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